FCC Part 15B Measurement and Test Report

For

Verykool USA Inc

3636 Nobel Drive, Suite 325 San Diego, CA 92122

FCC ID: WA6S758

Test Standards: FCC Part 15 Subpart B

Product Description: Android phone

Tested Model: S758

Report No.: <u>STR12118097I-4</u>

Tested Date: <u>2012-11-08 to 2012-11-28</u>

Issued Date: <u>2012-11-28</u>

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Note: This test report is limited to the above client company and the product model only. It may not be duplicated without prior permitted by SEM.Test Compliance Service Co., Ltd

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1. GENERAL INFORMATION

1.1 Product Description for Equipment Under Test (EUT)

Client Information

Applicant: Verykool USA Inc

Address of applicant: 3636 Nobel Drive, Suite 325 San Diego, CA 92122

Manufacturer: FUKDA TECHNOLOGY CO., LTD

Address of manufacturer: East Unit, 4th Floor, No.2 Building, Zhenhua Laobing

Industrial Park, No.44 Tiezai Road, Xixiang Town,

Bao'an District, Shenzhen, China

General Description of EUT				
Product Name:	Android phone			
Trade Name:	Verykool			
Model No.:	S758			
Rated Voltage:	DC 3.7V Li-ion Battery (Model:GS3)			
Dower Adeptor Models	TNC-L108C-CH			
Power Adapter Model:	(Input: AC 100-240V, Output: DC 5V 800mA)			
Note: The test data is gathered from a production sample provided by the manufacturer.				

Technical Characteristics of EUT				
Rated Voltage:	DC 3.7V Li-ion Battery, Adapter DC5V			
Rated Current:	/			
Dower Adeptor Models	A261-0500500U (Input: AC 100-240V,50/60Hz 0.2A,			
Power Adapter Model:	Output: DC 5V,500mA)			
Highest Internal Frequency:	26MHz			
Classification of ITE:	В			
Support Interface:	Earphone Port, DC Power Port			

1.2 Test Standards

The following report is prepared on behalf of the Verykool USA Inc in accordance with Part 2, Subpart J, and Part 15, Subparts A and B of the Federal Communication Commissions rules.

The objective is to determine compliance with FCC Part 15, Subpart B, and section 15.205, 15.107, and 15.109 rules.

Maintenance of compliance is the responsibility of the manufacturer. Any modification of the product, which result in lowering the emission, should be checked to ensure compliance has been maintained.

1.3 Test Methodology

All measurements contained in this report were conducted with ANSI C63.4-2003, American National Standard for Methods of Measurement of Radio-Noise Emissions from Low-Voltage Electrical and Electronic Equipment in the range of 9 kHz to 40 GHz.

1.4 Test Facility

• FCC – Registration No.: 994117

SEM.Test Compliance Services Co., Ltd. EMC Laboratory has been registered and fully described in a report filed with the (FCC) Federal Communications Commission. The acceptance letter from the FCC is maintained in our files and the Registration is 994117.

• Industry Canada (IC) Registration No.: 7673A

The 3m Semi-anechoic chamber of SEM.Test Compliance Services Co., Ltd. has been registered by Certification and Engineering Bureau of Industry Canada for radio equipment testing with Registration No.: 7673A.

• CNAS Registration No.: L4062

Shenzhen SEM.Test Electronics Service Co., Ltd. is a testing organization accredited by China National Accreditation Service for Conformity Assessment (CNAS) according to ISO/IEC 17025. The accreditation certificate number is L4062. All measurement facilities used to collect the measurement data are located at 3/F, Jinbao Commerce Building, Xin'an Fanshen Road, Bao'an District, Shenzhen, P.R.C (518101)

1.5 EUT Setup and Operation Mode

The equipment under test (EUT) was configured to measure its highest possible emission level. The test modes were adapted according to the operation manual for use, more detailed description as follows:

Test Mode List:

Test Mode	Description	Remark
TM1	Playing & Charging	Playing multimedia from TF card
TM2	Downloading	Reading &writing

EUT Cable List and Details

Cable Description	Length (M)	Shielded/Unshielded	With Core/Without Core
DC Power Cable	0.9	Unshielded	Unshielded
Earphone Cable	0.9	Unshielded	Without Ferrite

Auxiliary Equipment List and Details

Description	Manufacturer	Model	Serial Number
Notebook	SAMSUNG	NP-R20	124V93FP30082V

Special Cable List and Details

Cable Description	Length (M)	Shielded/Unshielded	With Core/Without Core
USB Cable	1.0	Shielded	Without Ferrite

2. SUMMARY OF TEST RESULTS

FCC Rules	Description of Test Item	Result
§ 15.107 (a)	Conducted Emissions	Compliant
§ 15.109 (a)	Radiated Emissions	Compliant

N/A: not applicable

3. §15.107 (a) CONDUCTED EMISSIONS

3.1 Measurement Uncertainty

Base on NIS 81, The Treatment of Uncertainty in EMC Measurements, the best estimate of the uncertainty of any conducted emissions measurement is ± 2.88 dB.

3.2 Test Equipment List and Details

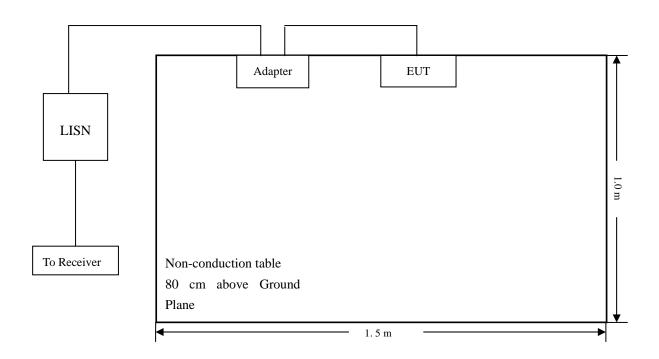
Description	Manufacturer	Model	Serial Number	Cal. Date	Due. Date
EMI Test Receiver	Rohde & Schwarz	ESPI	101611	2012-03-28	2013-03-27
L.I.S.N	Schwarz beck	NSLK8126	8126-224	2012-03-28	2013-03-27
Pulse Limiter	Rohde & Schwarz	ESH3-Z2	100911	2012-03-28	2013-03-27

Statement of Traceability: All calibrations have been performed per the NVLAP requirements traceable to the NIST.

3.3 Test Procedure

Test is conducting under the description of ANSI C63.4-2003, American National Standard for Methods of Measurement of Radio-Noise Emissions from Low-Voltage Electrical and Electronic Equipment in the range of 9 kHz to 40 GHz.

3.4 Basic Test Setup Block Diagram



3.5 Environmental Conditions

Temperature:	23 °C
Relative Humidity:	52%
ATM Pressure:	1011 mbar

3.6 Summary of Test Results/Plots

According to the data in section 3.7, the EUT <u>complied with the FCC Part 15.107(a)</u> Conducted margin for a Class B device, with the *worst* margin reading of:

-7.84 dB at 2.27 MHz in the Line, Peak detector, 0.15-30MHz

3.7 Conducted Emissions Test Data

Plot of Conducted Emissions Test Data

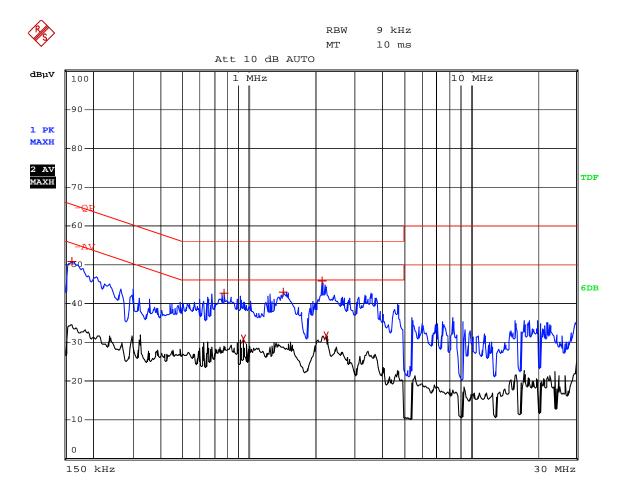
EUT: Android phone

Tested Model: S758

Operating Condition: Charging & Playing

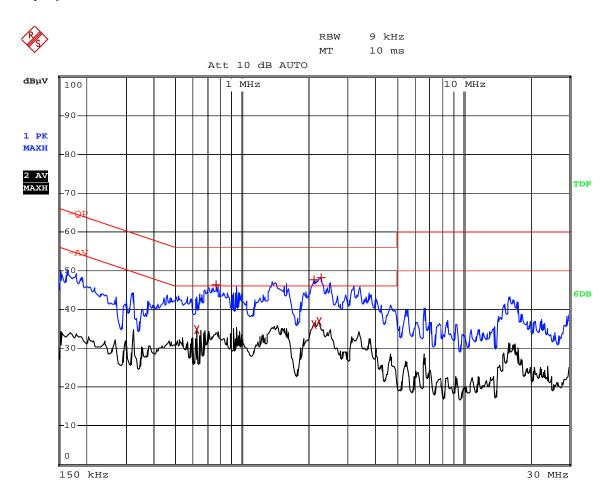
Comment: AC 120V/60Hz, Adapter DC5V

Test Specification: Neutral



		EDIT PEAK LIST (Prescan Results)	
Tra	ce1:	-QP		
Tra	ce2:	-AV		
Tra	ce3:			
	TRACE	FREQUENCY	LEVEL dBµV	DELTA LIMIT dB
1	Max Peak	162 kHz	50.71	-14.64
1	Max Peak	774 kHz	42.63	-13.36
2	Average	946 kHz	30.74	-15.25
1	Max Peak	1.422 MHz	42.88	-13.11
1	Max Peak	2.138 MHz	45.82	-10.17
2	Average	2.222 MHz	31.70	-14.29

Test Specification: Line



	EDIT PEAK LIST (Prescan Results)	
Trace1:	-QP		
Trace2:	-AV		
Trace3:			
TRACE	FREQUENCY	LEVEL dBµV	DELTA LIMIT dB
2 Average	622 kHz	34.81	-11.18
1 Max Peak	766 kHz	46.35	-9.64
1 Max Peak	2.118 MHz	47.55	-8.44
2 Average	2.118 MHz	36.01	-9.98
2 Average	2.234 MHz	36.86	-9.13
1 Max Peak	2.27 MHz	48.15	-7.84

4. §15.109(a)- RADIATED EMISSION

4.1 Measurement Uncertainty

Base on NIS 81, The Treatment of Uncertainty in EMC Measurements, the best estimate of the uncertainty of any radiation emissions measurement is \pm 5.10 dB.

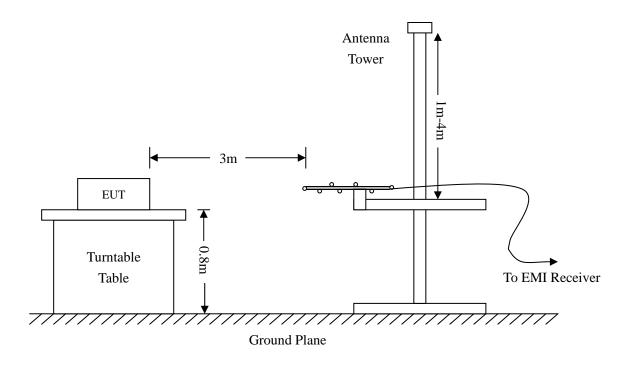
4.2 Test Equipment List and Details

Description	Manufacturer	Model	Serial Number	Cal. Date	Due. Date
Spectrum Analyzer	R&S	FSP	836079/035	2012-03-28	2013-03-27
EMI Test Receiver	R&S	ESVB 825471/005		2012-03-28	2013-03-27
Pre-amplifier	Agilent	8447F	3113A06717	2012-03-28	2013-03-27
Pre-amplifier	Compliance Direction	PAP-0118	24002	2012-03-28	2013-03-27
Trilog Broadband Antenna	SCHWARZBECK	VULB9163	9163-333	2012-02-25	2013-02-24
Horn Antenna	ETS	3117	00086197	2012-02-25	2013-02-24

4.3 Test Procedure

The setup of EUT is according with per ANSI C63.4-2003 measurement procedure. The specification used was with the FCC Part 15.109 Limit.

The external I/O cables were draped along the test table and formed a bundle 30 to 40 cm long in the middle. The spacing between the peripherals was 10 cm.



4.4 Test Receiver Setup

During the radiated emission test for above 1GHz, the test receiver was set with the following configurations:

For peak detector:

RBW = 1000kHz, VBW = 3000kHz, Sweep Time = Auto

For average detector:

RBW = 1000kHz, VBW = 10Hz, Sweep Time = Auto

4.5 Corrected Amplitude & Margin Calculation

The Corrected Amplitude is calculated by adding the Antenna Factor and the Cable Factor, and subtracting the Amplifier Gain from the Amplitude reading. The basic equation is as follows:

Corr. Ampl. = Indicated Reading – Corr. Factor

The "Margin" column of the following data tables indicates the degree of compliance with the applicable limit. For example, a margin of $-6dB\mu V$ means the emission is $6dB\mu V$ below the maximum limit for a Class B device. The equation for margin calculation is as follows:

Margin = Corr. Ampl. – FCC Part 15.109(a) Limit

4.6 Environmental Conditions

Temperature:	23 °C
Relative Humidity:	55 %
ATM Pressure:	1011 mbar

4.7 Summary of Test Results/Plots

According to the data, the EUT complied with the FCC Part 15.109(a) rule, and had the worst margin of:

-3.58 dB at 31.0706MHz in the Vertical polarization, Charging &Playing Mode, 9kHz to 1 GHz, 3Meters

-2.30 dB at 301.4224 MHz in the Horizontal polarization, Downloading Mode 9kHz to 1 GHz, 3Meters

Plot of Radiated Emissions Test Data

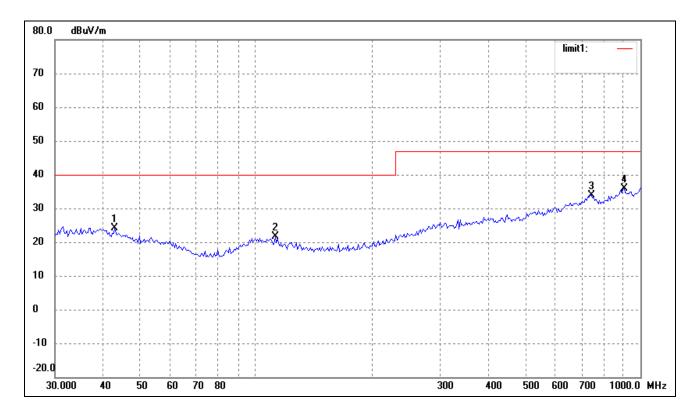
EUT: Android phone

Tested Model: S758

Operating Condition: Charging &Playing

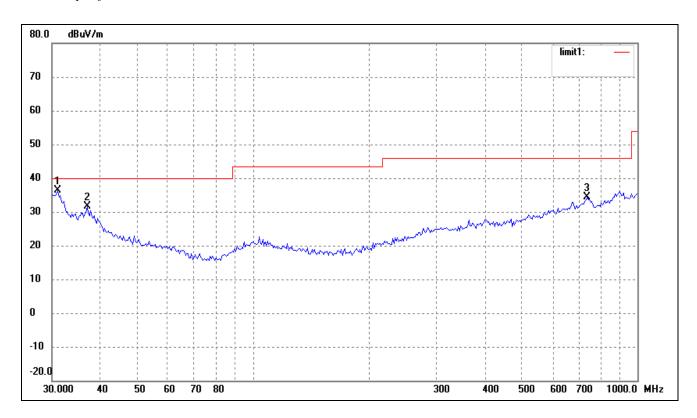
Comment: Playing multimedia from TF card

Test Specification: Horizontal



No.	Frequency	Reading	Correct	Result	Limit	Margin	Degree	Height	Remark
	(MHz)	(dBuV/m)	dB/m	(dBuV/m)	(dBuV/m)	(dB)	(•)	(cm)	
1	42.8998	15.31	8.79	24.10	40.00	-15.90	224	100	peak
2	112.1305	16.10	5.65	21.75	40.00	-18.25	167	200	peak
3	744.8661	16.02	17.95	33.97	47.00	-13.03	286	200	peak
4	906.4824	16.72	19.15	35.87	47.00	-11.13	360	100	peak

Test Specification: Vertical



No.	Frequency	Reading	Correct	Result	Limit	Margin	Degree	Height	Remark
	(MHz)	(dBuV/m)	dB/m	(dBuV/m)	(dBuV/m)	(dB)	(•)	(cm)	
1	31.0706	28.20	8.22	36.42	40.00	-3.58	254	100	peak
2	37.0248	22.30	9.21	31.51	40.00	-8.49	180	100	peak
3	739.6604	16.21	18.07	34.28	46.00	-11.72	226	100	peak

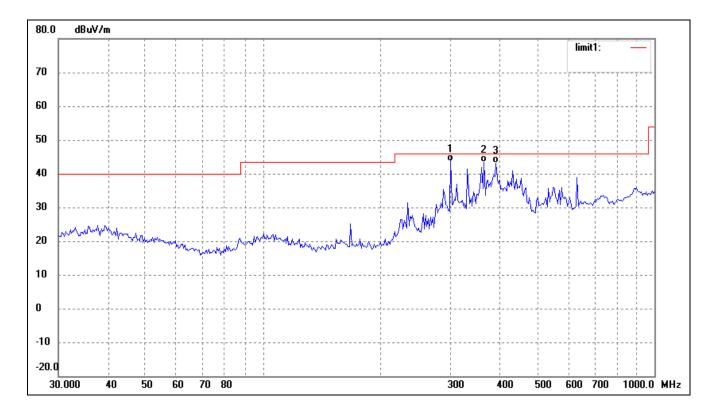
Plot of Radiated Emissions Test Data

EUT: Android phone

Tested Model: S758

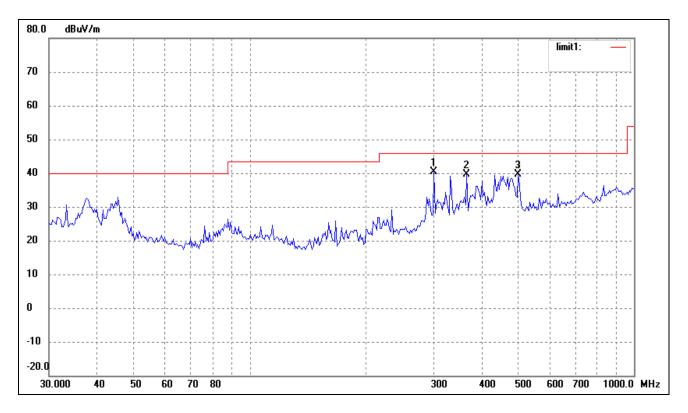
Operating Condition: Downloading
Comment: Connect to PC

Test Specification: Horizontal



No.	Frequency	Reading	Correct	Result	Limit	Margin	Degree	Height	Remark
	(MHz)	(dBuV/m)	dB/m	(dBuV/m)	(dBuV/m)	(dB)	(•)	(cm)	
1	301.4224	33.50	10.20	43.70	46.00	-2.30	261	100	QP
2	366.8231	32.59	10.67	43.26	46.00	-2.74	360	100	QP
3	393.4724	31.94	11.24	43.18	46.00	-2.82	114	100	QP

Test Specification: Vertical



No.	Frequency	Reading	Correct	Result	Limit	Margin	Degree	Height	Remark
	(MHz)	(dBuV/m)	dB/m	(dBuV/m)	(dBuV/m)	(dB)	(•)	(cm)	
1	301.4224	30.16	10.20	40.36	46.00	-5.64	274	100	peak
2	366.8231	28.92	10.67	39.59	46.00	-6.41	225	200	peak
3	499.4247	27.43	12.18	39.61	46.00	-6.39	168	100	peak

Note: Testing is carried out with frequency rang 9kHz to 1GHz, which emissions below 30MHz are attenuated more than 20dB below the permissible limits or the field strength are not list above.